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AOD4126

100V N-Channel MOSFET

SDMOS™

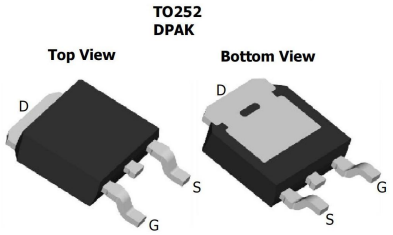
General Description

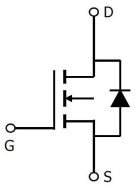
The AOD4126are fabricated with SDMOS™ trench technology that combines excellent $R_{DS(ON)}$ with low gate charge.The result is outstanding efficiency with controlled switching behavior. This universal technology is well suited for PWM, load switching and general purpose applications.

Product Summary

V_{DS}	100V
I_D (at V_{GS}=10V)	43A
$R_{DS(ON)}$ (at V_{GS}=10V)	< 24mΩ
$R_{DS(ON)}$ (at V_{GS} = 7V)	< 30mΩ

100% UIS Tested
100% R_g Tested





Orderable Part Number	Package Type	Form	Minimum Order Quantity
	TO-252	Tape & Reel	2500

Absolute Maximum Ratings T_A=25℃ unless otherwise noted

Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	100	V
Gate-Source Voltage		V_{GS}	±25	V
Continuous Drain Current [B]	T_C=25℃	I_D	43	A
	T_C=100℃		30	
Pulsed Drain Current [C]		I_{DM}	100	
Continuous Drain Current [A]	T_A=25℃	I_{DSM}	7.5	A
	T_A=70℃		6	
Avalanche Current [C]		I_{AS}, I_{AR}	28	A
Avalanche energy L=0.1mH [C]		E_{AS}, E_{AR}	39	mJ
Power Dissipation [B]	T_C=25℃	P_D	100	W
	T_C=100℃		50	
Power Dissipation [A]	T_A=25℃	P_{DSM}	3	W
	T_A=70℃		1.9	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 175	℃

Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	8	10	℃/W
Maximum Junction-to-Ambient [A D]	Steady-State		35	42	℃/W
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	1	1.5	℃/W

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Electrical Characteristics (T_J=25℃ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=250μA, V_{GS}=0V	100			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=100V, V_{GS}=0V			10	μA
		T_J=55℃			50	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}= ±25V			100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=250μA	2	3.3	4	V
$I_{D(ON)}$	On state drain current	V_{GS}=10V, V_{DS}=5V	100			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=10V, I_D=20A		19	24	mΩ
		T_J=125℃		36	43	
		V_{GS}=7V, I_D=15A		23.5	30	mΩ
g_{FS}	Forward Transconductance	V_{DS}=5V, I_D=20A		34		S
V_{SD}	Diode Forward Voltage	I_S=1A,V_{GS}=0V		0.66	1	V
I_S	Maximum Body-Diode Continuous Current				40	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=50V, f=1MHz	1400	1770	2200	pF
C_{oss}	Output Capacitance		115	165	214	pF
C_{rss}	Reverse Transfer Capacitance		33	55	80	pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz	0.3	0.65	1.0	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	V_{GS}=10V, V_{DS}=50V, I_D=20A	14	28	42	nC
Q_{gs}	Gate Source Charge		4	9	14	nC
Q_{gd}	Gate Drain Charge		6	10	14	nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=10V, V_{DS}=50V, R_L=2.5Ω, R_{GEN}=3Ω		12		ns
t_r	Turn-On Rise Time			4		ns
$t_{D(off)}$	Turn-Off DelayTime			17		ns
t_f	Turn-Off Fall Time			5		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=20A, dI/dt=500A/μs	12	20	26	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=20A, dI/dt=500A/μs	60	82	110	nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The Power dissipation P_{DSM} is based on $R_{\theta JA}$ and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(MAX)}$=175° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$=175° C. Ratings are based on low frequency and duty cycles to keep initial T_J =25° C.

D. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$=175° C. The SOA curve provides a single pulse rating.

G. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

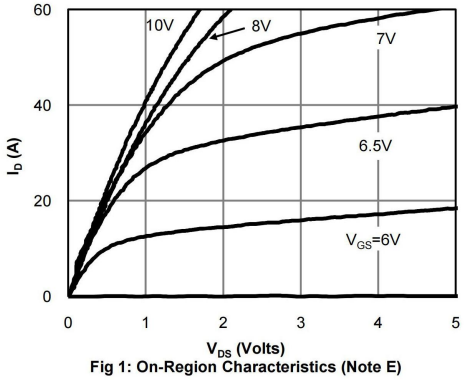


Fig 1: On-Region Characteristics (Note E)

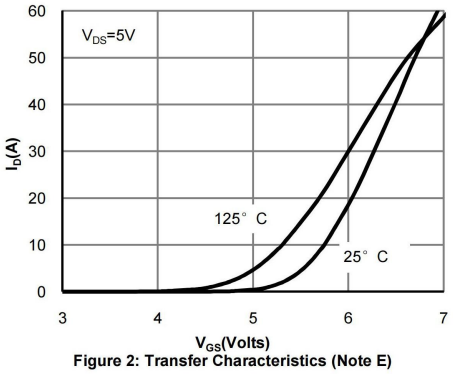


Figure 2: Transfer Characteristics (Note E)

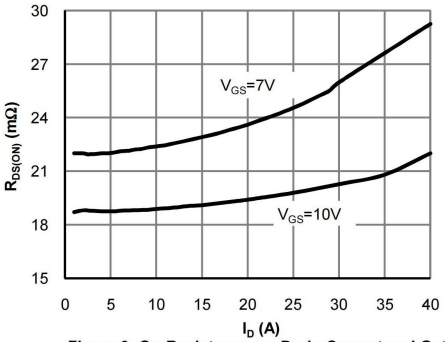


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

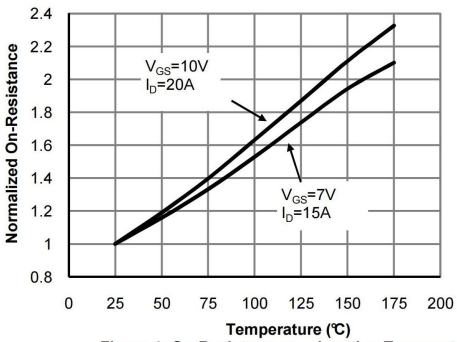


Figure 4: On-Resistance vs. Junction Temperature (Note E)

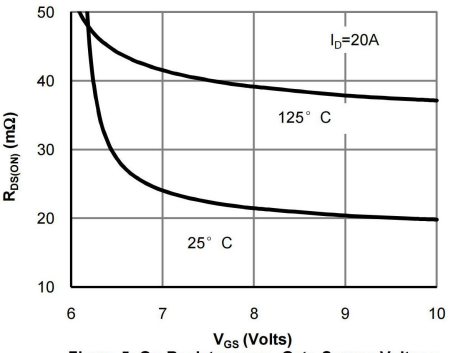


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

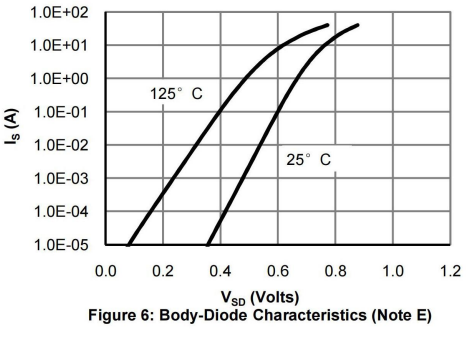


Figure 6: Body-Diode Characteristics (Note E)

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

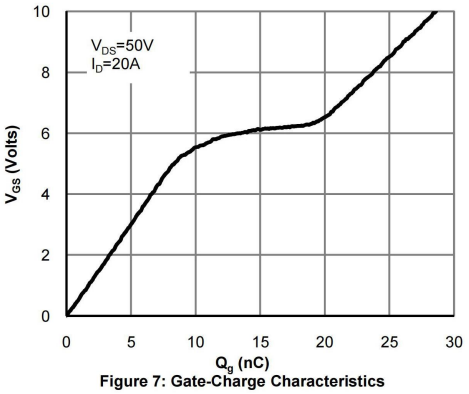


Figure 7: Gate-Charge Characteristics

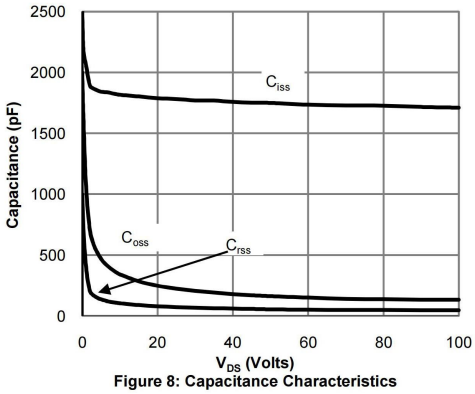


Figure 8: Capacitance Characteristics

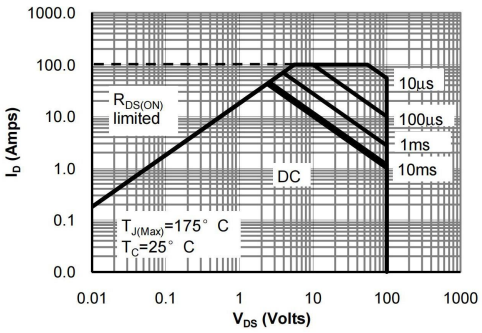


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

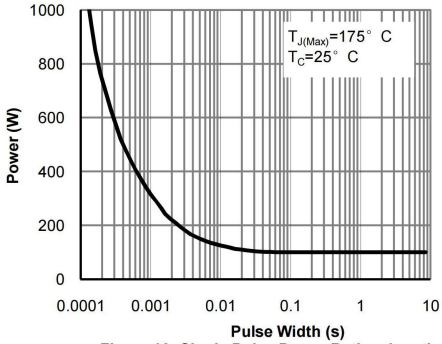


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

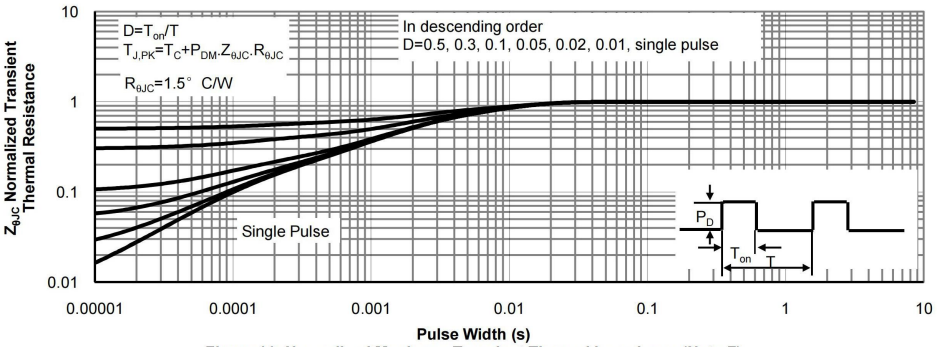


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

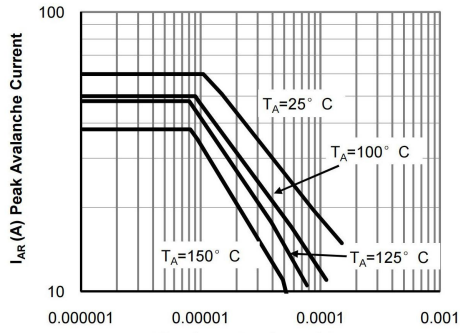


Figure 12: Single Pulse Avalanche capability (Note C)

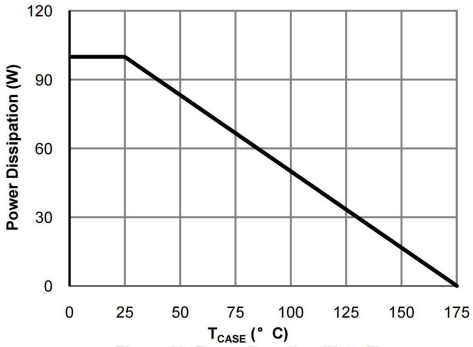


Figure 13: Power De-rating (Note F)

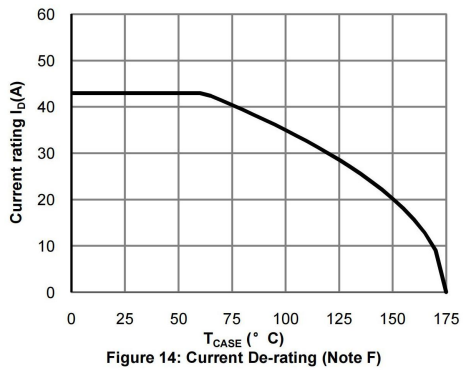


Figure 14: Current De-rating (Note F)

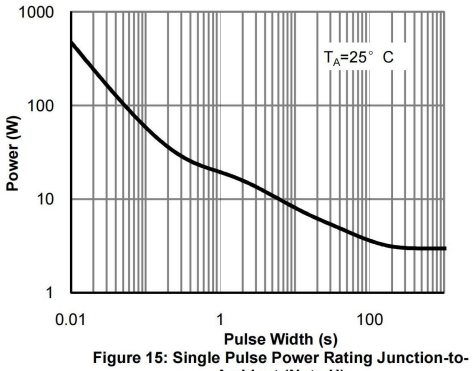


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

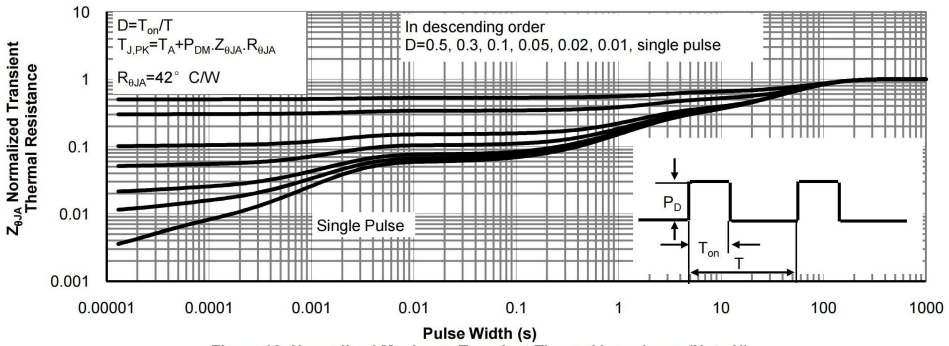


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

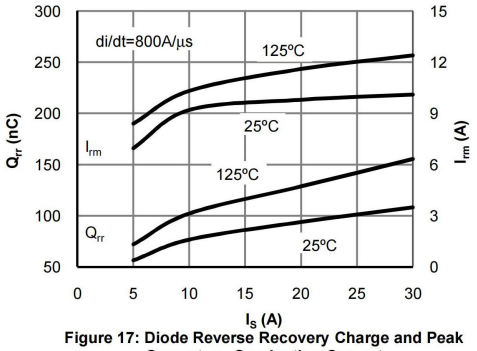


Figure 17: Diode Reverse Recovery Charge and Peak Current vs. Conduction Current

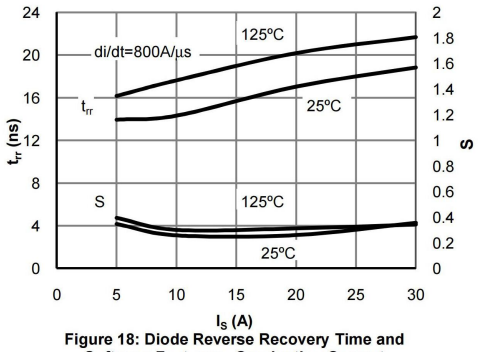


Figure 18: Diode Reverse Recovery Time and Softness Factor vs. Conduction Current

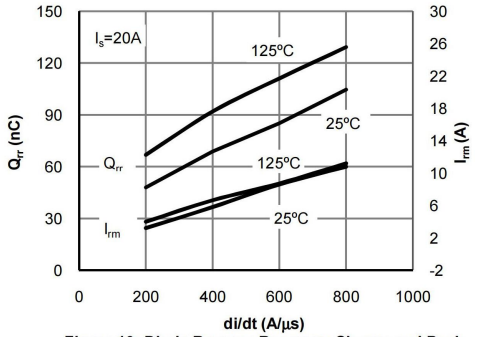


Figure 19: Diode Reverse Recovery Charge and Peak Current vs. di/dt

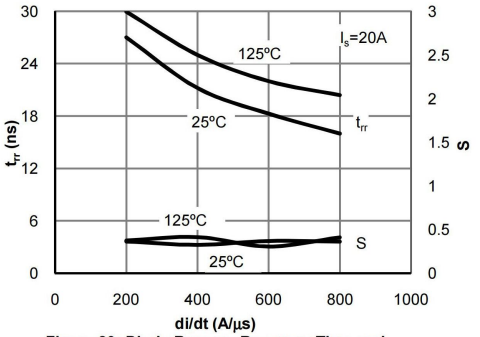
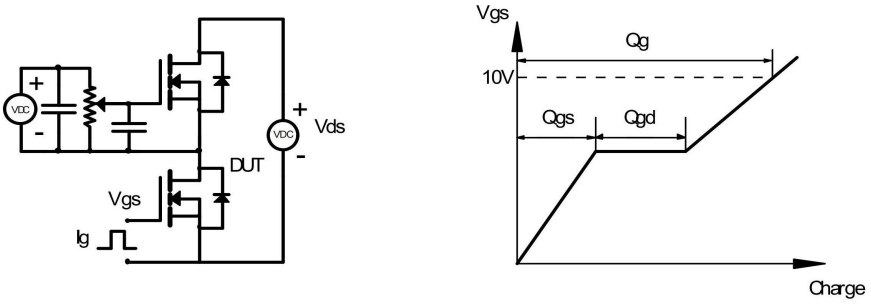


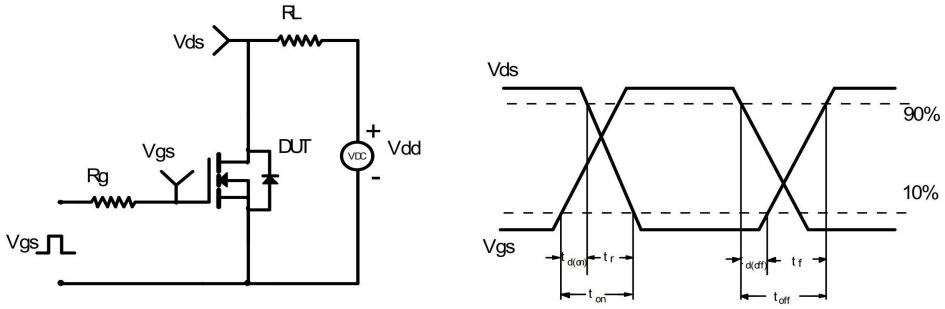
Figure 20: Diode Reverse Recovery Time and Softness Factor vs. di/dt

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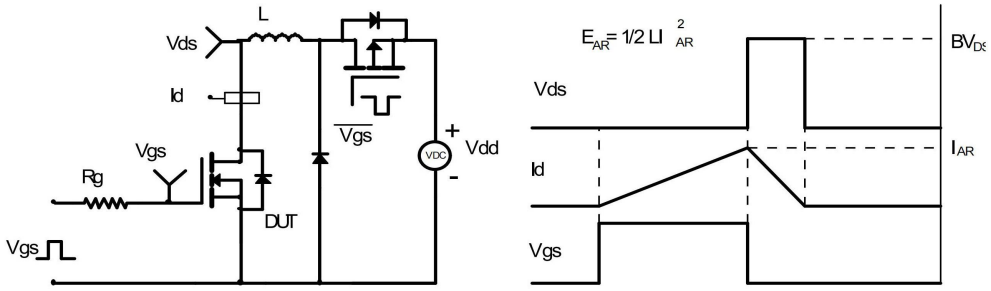
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

